SN54164, SN54LS164, SN74164, SN74LS164 8-BIT PARALLEL-OUT SERIAL SHIFT REGISTERS

MARCH 1974 - REVISED MARCH 1988

- Gated Serial Inputs
- Fully Buffered Clock and Serial Inputs
- Asynchronous Clear

TYPE	TYPICAL MAXIMUM CLOCK FREQUENCY	TYPICAL POWER DISSIPATION
′164	36 MHz	21 mW per bit
'LS164	36 MHz	10 mW per bit

description

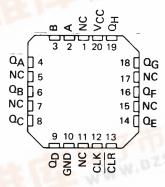
These 8-bit shift registers feature gated serial inputs and an asynchronous clear. The gated serial inputs (A and B) permit complete control over incoming data as a low at either input inhibits entry of the new data and resets the first flip-flop to the low level at the next clock pulse. A high-level input enables the other input which will then determine the state of the first flip-flop. Data at the serial inputs may be changed while the clock is high or low, but only information meeting the setup-time requirements will be entered. Clocking occurs on the low-to-high-level transition of the clock input. All inputs are diode-clamped to minimize transmission-line effects.

The SN54164 and SN54LS164 are characterized for operation over the full military temperature range of $-55\,^{\circ}\text{C}$ to 125 $\,^{\circ}\text{C}$. The SN74164 and SN74LS164 are characterized for operation from 0 $\,^{\circ}\text{C}$ to 70 $\,^{\circ}\text{C}$.

SN54164, SN54LS164...J OR W PACKAGE SN74164...N PACKAGE SN74LS164...D OR N PACKAGE (TOP VIEW)

ΑC	1	U 14	
в□	2	13	Цαн
$Q_A \square$	3	12	\square_{G}
$\alpha_{B} \square$	4	11	ΩF
$a_{C} \square$	5	10	DαE
$\sigma_{D} \square$	6	9	CLR
GND 🛚	7	8	CLK

SN54LS164 . . . FK PACKAGE (TOP VIEW)



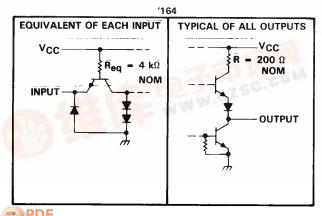
NC - No internal connection

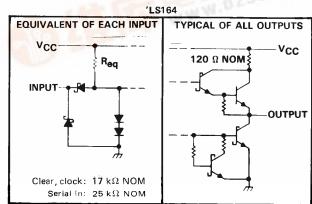
FUNCTION TABLE

	INPUTS				OUTP	UTS
CLEAR	CLOCK	Α	В	QA	α_{B}	Q _H
L	X	Х	X	L	L	07.2V
н	L	X	X	Q _{A0}	Q_{B0}	Q _{H0}
Н	1	н	Н	Н	Q_{An}	α_{Gn}
н	1	L	X	L	\mathbf{Q}_{An}	Q_{Gn}
H	1	×	L	L	Q_{An}	Q_{Gn}

- H = high level (steady state), L = low level (steady state)
- X = irrelevant (any input, including transitions)
- \uparrow = transition from low to high level.
- $\Omega_{A0}, \Omega_{B0}, \Omega_{H0}$ = the level of Ω_A, Ω_B , or Ω_H , respectively, before the indicated steady-state input conditions were established.
- Q_{An}, Q_{Gn} = the level of Q_A or Q_G before the most-recent ↑ transition of the clock; indicates a one-bit shift.

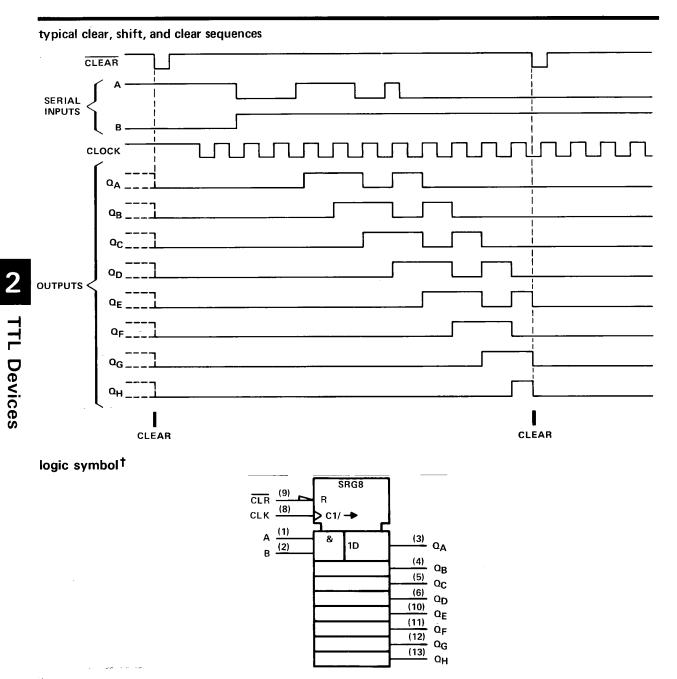
schematics of inputs and outputs



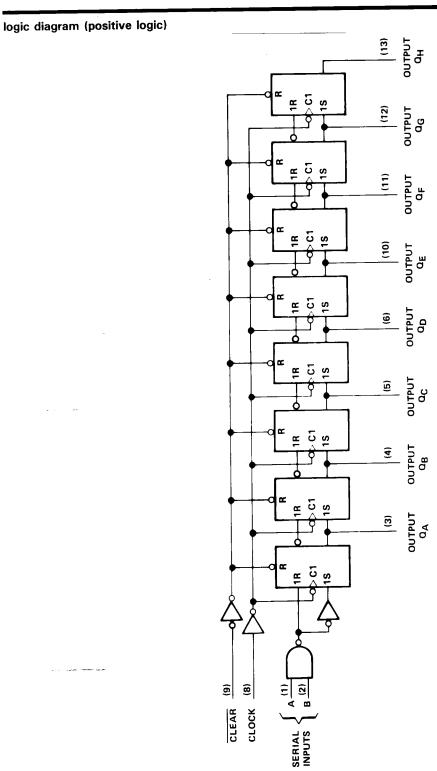




SN54164, SN54LS164, SN74164, SN74LS164 8-BIT PARALLEL-OUT SERIAL SHIFT REGISTERS



[†]This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers shown are for D, J, N, and W packages.



Pin numbers shown are for D, J, N, and W packages.

SN54164, SN74164 **8-BIT PARALLEL-OUT SERIAL SHIFT REGISTERS**

absolute maximum ratings over oprating	maximum ratings over oprating free-air temperature range (unless otherwise noted) oly voltage, V _{CC} (see Note 1)	
Supply voltage, VCC (see Note 1)		
Operating free-air temperature range:	SN5416455°C to 125°C	
	SN74164	
Storage temperature range	– 65 °C to 150 °C	

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		SN5416	4	;	SN7416	4	UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Supply voltage, VCC	4.5	5	5.5	4.75	5	5.25	V
High-level output current, IOH			-400			-400	μΑ
Low-level output current, IQL			8			8	mA
Clock frequency, fclock	0		25	0		25	MHz
Width of clock or clear input pulse, tw	20			20			ns
Data setup time, t _{su} (see Figure 1)	15	·		15			ns
Data setup time, t _{su} (Clear Inactive) (see Figure 1)	20			20			ns
Data hold time, th (see Figure 1)	5			5	_	· · · · · · · · · · · · · · · · · · ·	ns
Operating free-air temperature, TA	- 55		125	0		70	°C_

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

				SN54164		,	UNIT		
PARAMETER		TEST CONDITIONS†	MIN	TYP‡	MAX	MIN	TYP‡	MAX	ONT
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage				8.0			8.0	V
VIK	Input clamp voltage	V _{CC} = MIN, I _I = -12 mA			-1.5			-1.5	V
Voн	High-level output voltage	V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = 0.8 V, I _{OH} = -400 μA	2.4	3.2		2.4	3.2		V
VOL	Low-level output voltage	$V_{CC} = MIN, V_{IH} = 2 V,$ $V_{IL} = 0.8 V, I_{OL} = 8 mA$		0.2	0.4		0.2	0.4	V _
\vdash_{i}	Input current at maximum input voltage	$V_{CC} = MAX, V_1 = 5.5 V,$			1			1	mA
T _{IH}	High-level input current	V _{CC} = MAX, V ₁ = 2.4 V			40			40	μA
11L	Low-level input current	V _{CC} = MAX, V _I = 0.4 V			-1.6			-1.6	mA
los	Short-circuit output current §	V _{CC} = MAX	-10		-27.5	-9		-27.5	mA
F-03		$V_{CC} = MAX$, $V_{I(clock)} = 0.4$	V	30			30		mA
Icc	Supply current	See Note 2 V _{I(clock)} = 2.4	V	37	54		37	54]'''

[†] For conditions shown at MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 2: I_{CC} is measured with outputs open, serial inputs grounded, and a momentary ground, then 4.5 V, applied to clear.

switching characteristics, VCC = 5 V, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS			TYP	MAX	UNIT
f _{max}	Maximum clock frequency		C _L = 15 pF	25	36		MHz
IIIax	Propagation delay time, high-to-low-level		C _L = 15 pF		24	36	ns
^t PHL			C _L = 50 pF		28	42	1
	Propagation delay time, low-to-high-level	$R_L = 800 \Omega$,	C _L = 15 pF	8	17	27	ns
^t PLH	Q outputs from clock input	See Figure 1	C _L = 50 pF	10	20	30] ""
	Propagation delay time, high-to-low-level		C _L = 15 pF	10	21	32	ns
tPHL		- L		10	25	37	<u> </u>



[‡] All typical values are at V_{CC} = 5 V, T_A = 25 $^{\circ}$ C.

[§] Not more than two outputs should be shorted at a time.

SN54LS164, SN74LS164 8-BIT PARALLEL-OUT SERIAL SHIFT REGISTERS

absolute maximum ratings over operating	free-air temperature	range (unless other	wise noted)
Supply voltage, VCC (see Note 1)			7 V
Input voltage			7 V
Operating free-air temperature range: S	N54LS164		-55°C to 125°C
Si	N74LS164		0°C to 70°C
Storage temperature range			-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		S	N54LS1	64	S	N74LS1	64	LIBUT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.7			0.8	V
ЮН	High-level output current			- 0.4			- 0.4	mΑ
lOL	Low-level output current			4			8	mA
fclock	Clock frequency	0		25	0		25	MHz
tw	Width of clock or clear input pulse	20			20			ns
t _{su}	Data setup time (See Figure 1)	15			15			ns
t _{su}	Clear inactive setup time (See Figure 1)	20			20		_	ns
th	Data hold time (See Figure 1)	5		•	5			ns
TA	Operating free-air temperature	– 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

242445752	TEST CONDITIONS [†]		SN54LS164			S	UNIT		
PARAMETER	TEST CONDITIONS.	:21 CONDITIONS			MIN TYP‡ MAX		TYP [‡]	MAX	ONIT
VIK	V _{CC} = MIN, I _I = -18 mA	·			- 1.5			- 1 .5	V
Voн	$V_{CC} = MIN$, $V_{IH} = 2 V$, V_{IL} $I_{OH} = -0.4 \text{ mA}$	= MAX,	2.5	3.5		2.7	3.5		>
	$V_{CC} = MIN, V_{IH} = 2 V,$	IOL = 4 mA		0.25	0.4		0.25	0.4	
v_{OL}	V _{IL} = MAX	I _{OL} = 8 mA					0.35	0.5	v
l _l	V _{CC} = MAX, V _I = 7 V				0.1			0.1	mA
liH	$V_{CC} = MAX$, $V_I = 2.7 V$			20			20		μΑ
ŀιL	$V_{CC} = MAX$, $V_I = 0.4 V$				-0.4			-0.4	mA
los	V _{CC} = MAX		- 20		- 100	- 20		- 100	mA
lcc	V _{CC} = MAX, See Note 3			16	27		16	27	mA

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
fmax	Maximum clock frequency		25	36		MHz
tPHL	Propagation delay time, high-to-low-level Q outputs from clear	$R_1 = 2 k\Omega$, $C_1 = 15 pF$,		24	36	ns
THL	input	2 mas, se ,				
*	Propagation delay time, low-to-high-level Q outputs from clock	See Figure 1		17	27	ns
^t PLH	input	occ riguic i				
*	Propagation delay time, high-to-low-level Q outputs from clock			21	32	ns
^t PHL	input			21	32	'is



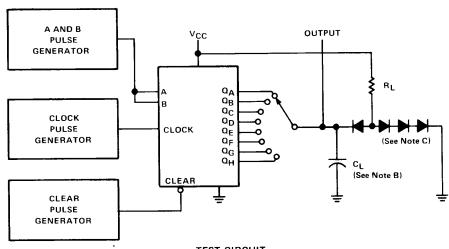
 $^{^{\}ddagger}$ All typical values are at V_{CC} = 5 V, T_A = 25 °C.

Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

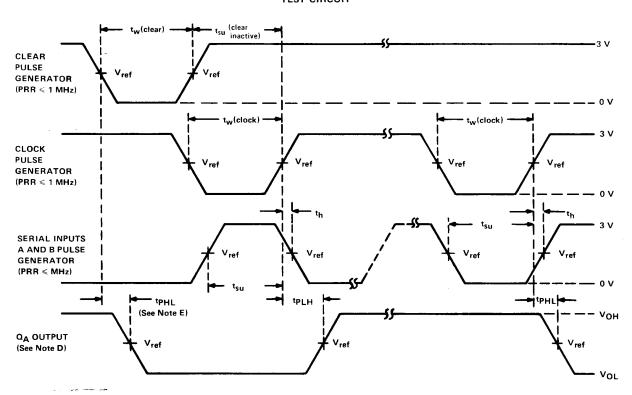
NOTE 3: I_{CC} is measured with outputs open, serial inputs grounded, the clock input at 2.4 V, and a momentary ground, then 4.5 V applied to clear.

SN54164, SN54LS164, SN74164, SN74LS164 **8-BIT PARALLEL-OUT SERIAL SHIFT REGISTERS**

PARAMETER MEASUREMENT INFORMATION



TEST CIRCUIT



VOLTAGE WAVEFORMS

- NOTES: A. The pulse generators have the following characteristics: duty cycle \leq 50%, $Z_{out} \approx$ 50 Ω ; for '164, $t_r \leq$ 10 ns, $t_f \leq$ 10 ns; and for LS164, $t_r \le 15$ ns, $t_f \le 6$ ns.
 - B. C_L includes probe and jig capacitance.
 - C. All diodes are 1N3064 or equivalent.
 - D. QA output is illustrated. Relationship of serial input A and B data to other Q outputs is illustrated in the typical shift sequence.
 - E. Outputs are set to the high level prior to the measurement of tpHL from the clear input.
 - F. For '164, $V_{ref} = 1.5 \text{ V}$; for 'LS164, $V_{ref} = 1.3 \text{ V}$.

FIGURE 1-SWITCHING TIMES



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